

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Daewon KWON

a / IDS  
E. Usillo  
11-19-01

Serial No.: New Application

Filed: September 27, 2001

For: METHODS AND APPARATUS FOR DETERMINING  
OPTICAL CONSTANTS OF SEMICONDUCTORS AND  
DIELECTRICS WITH INTERBAND STATES**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR §1.97 & §1.98**Assistant Commissioner of Patents  
Washington, D.C. 20231

September 27, 2001

Sir:

In the matter of the above-identified application, Applicant is submitting herewith copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration which were cited in the above-identified application.

This information disclosure statement is being submitted concurrently with the filing of the above-identified application.

Each of the documents listed on the attached form equivalent to Form PTO-1449 is in the English language.

It is respectfully requested that this Information Disclosure Statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account No. 01-2135 (178.39931X00) and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

A handwritten signature in cursive script, appearing to read "Ronald J. Shore", is written over a horizontal line.

Ronald J. Shore

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DKT. NO.

178.39931X00

SERIAL NO.

09/963638

INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Daewon KWON

FILING DATE

September 27, 2001

GROUP

09/27/01

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	6,049,220	04/11/00	Borden et al.			06/10/98
AB	5,883,518	03/16/99	Borden			04/24/96
AC	4,854,710	08/08/89	Opsal et al.			07/23/87
AD	5,966,019	10/12/99	Borden			04/24/96
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM							
AN							
AO							
AP							
AQ							
AR							
AS							
AT							

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	Tauc et al., "Optical Properties and Electronic Structure of Amorphous Germanium", <i>Phys. Stat. Sol.</i> 15, 627 (1966), pp. 627-637.
AV	J. Bourgoin et al., <i>Point Defects in Semiconductors II</i> , Springer-Verlag, Berlin, Heidelberg, New York 1983.
AW	
AX	
AY	
AZ	
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